

### FNK N-Channel Enhancement Mode Power MOSFET

#### **Description**

The FNK0203EB uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

#### **General Features**

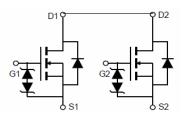
V<sub>DS</sub> =20V,I<sub>D</sub> =9A

 $R_{DS(ON)} < 9.8 m\Omega$  @  $V_{GS}$ =4.5V  $R_{DS(ON)} < 14.5 m\Omega$  @  $V_{GS}$ =2.5V

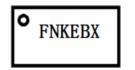
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- 2.5V Drive
- Common-drain type

### **Application**

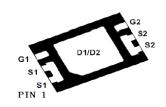
- Battery protection switch
- Mobile device battery charging and discharging



Schematic diagram



Marking and pin assignment



DFN2\*3-6 top view

#### **Package Marking and Ordering Information**

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
FNKEBX	FNK0203EB	DFN 2x3	-	-	-

#### Absolute Maximum Ratings (T<sub>C</sub>=25℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V <sub>DS</sub>	20	V
Gate-Source Voltage	V <sub>G</sub> S	±10	V
Drain Current-Continuous	I <sub>D</sub>	9	А
Pulsed Drain Current	I <sub>DM</sub>	36	Α
Maximum Power Dissipation	P <sub>D</sub>	1.5	W
Operating Junction and Storage Temperature Range	$T_{J},T_{STG}$	-55 To 150	$^{\circ}$ C

#### **Thermal Characteristic**

Thermal Resistance, Junction-to-Ambient (Note 2)	$R_{ heta JA}$	83	°C/W

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Electrical Characteristics (TC=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =250µA	20		-	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =20V,V <sub>GS</sub> =0V	-	-	1	μΑ
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±10V,V <sub>DS</sub> =0V	-	-	±10	μΑ
On Characteristics (Note 3)						
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS}=V_{GS}$ , $I_{D}=250\mu A$	0.5	0.7	1	V
Dunin Course On State Desistance	D	$V_{GS}$ =4.5V, $I_D$ =10A	-	7.4	9.8	- mΩ
Drain-Source On-State Resistance	R <sub>DS(ON)</sub> -	V <sub>GS</sub> =2.5V, I <sub>D</sub> =2.5A	-	9.2	14.5	
Forward Transconductance	<b>g</b> FS	V <sub>DS</sub> =4.5V,I <sub>D</sub> =5A	5	-	-	S
Dynamic Characteristics (Note4)			•	Į.		
Input Capacitance	C <sub>lss</sub>	V <sub>DS</sub> =10V,V <sub>GS</sub> =0V, F=1.0MHz	-	1655	-	PF
Output Capacitance	Coss		-	265	-	PF
Reverse Transfer Capacitance	C <sub>rss</sub>	r-1.0WInz	-	230	-	PF
Switching Characteristics (Note 4)						
Turn-on Delay Time	t <sub>d(on)</sub>		-	300	-	nS
Turn-on Rise Time	t <sub>r</sub>	$V_{DD}$ =10 $V$ , $I_{D}$ =5 $A$	-	1000	-	nS
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{GS}$ =10 $V$ , $R_{GEN}$ =50 $\Omega$	-	4000	-	nS
Turn-Off Fall Time	t <sub>f</sub>		-	2500	-	nS
Total Gate Charge	Qg	\/ 40\/ L 40A	-	29	-	nC
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS}=10V, I_{D}=10A,$	-	5.2	-	nC
Gate-Drain Charge	Q <sub>gd</sub>	V <sub>GS</sub> =10V	-	6.3	-	nC
Drain-Source Diode Characteristics	<u> </u>		•			
Diode Forward Voltage (Note 3)	V <sub>SD</sub>	V <sub>GS</sub> =0V,I <sub>S</sub> =2.3A	-	-	1.2	V

#### Notes:

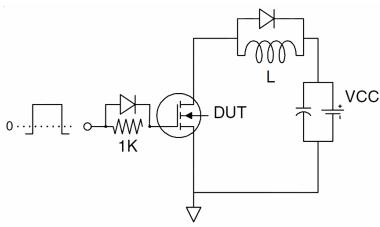
- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board,  $t \le 10$  sec.
- **3.** Pulse Test: Pulse Width ≤  $300\mu$ s, Duty Cycle ≤ 2%.
- 4. Guaranteed by design, not subject to production

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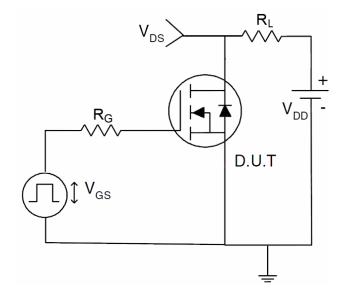


## **Test Circuit**

# 1) Gate Charge Test Circuit



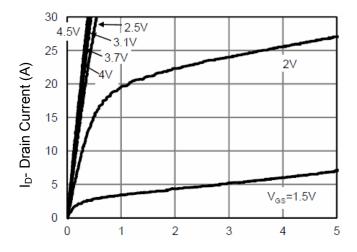
## 2) Switch Time Test Circuit



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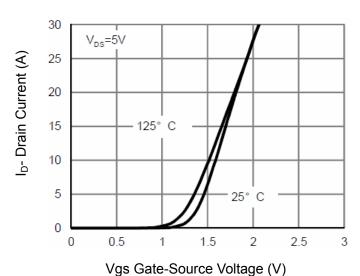


### **Typical Electrical and Thermal Characteristics (Curves)**



Vds Drain-Source Voltage (V)

Figure 1 Output Characteristics



**Figure 2 Transfer Characteristics** 

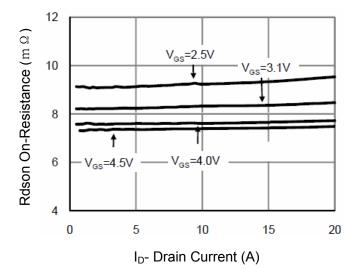
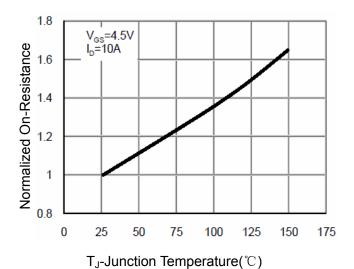


Figure 3 Rdson- Drain Current



**Figure 4 Rdson-Junction Temperature** 

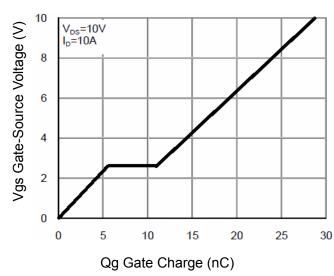


Figure 5 Gate Charge

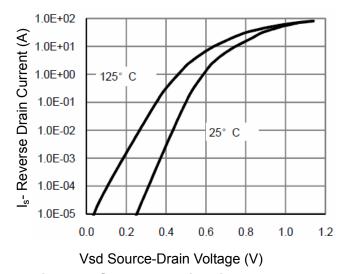


Figure 6 Source- Drain Diode Forward



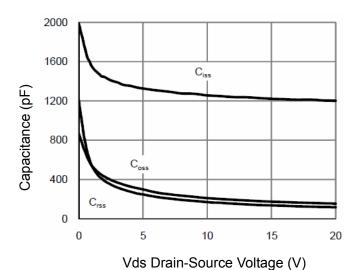


Figure 7 Capacitance vs Vds

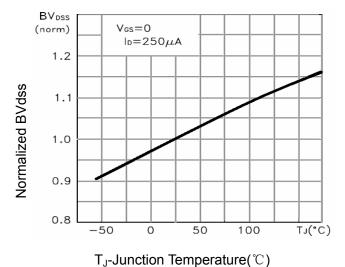


Figure 9 BV<sub>DSS</sub> vs Junction Temperature

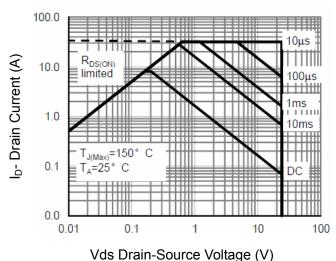
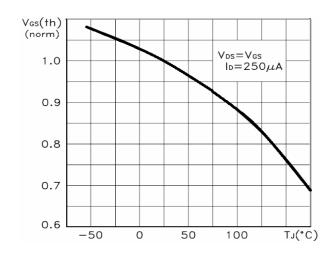
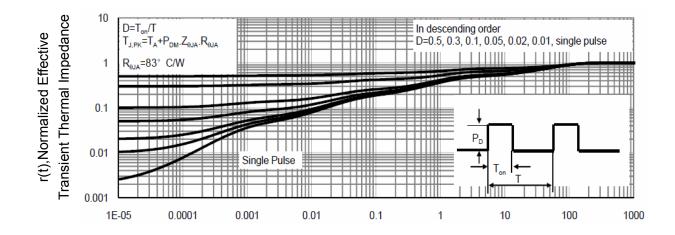


Figure 8 Safe Operation Area



 $\label{eq:TJ-Junction} $T_{J}$-Junction Temperature($^{\circ}$C)$ Figure 10 $V_{GS(th)}$ vs Junction Temperature$ 

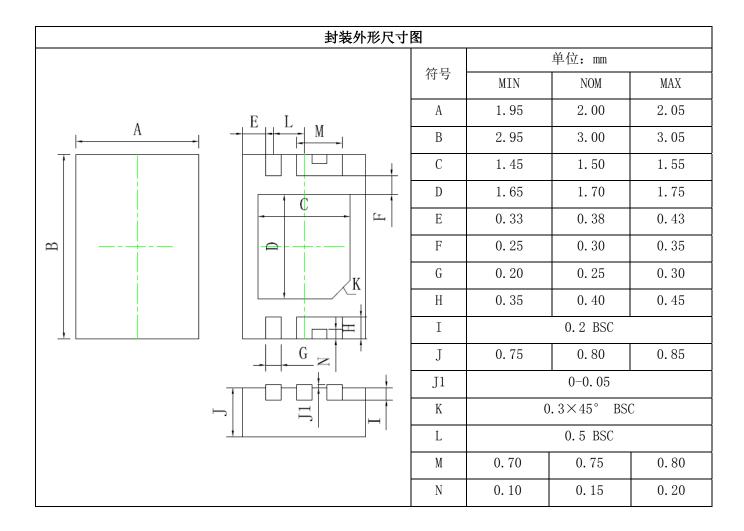


Square Wave Pluse Duration(sec)

Figure 11 Normalized Maximum Transient Thermal Impedance

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